



PTO/SB/08a/b (07-05)

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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/734,275-Conf. #1475
				Filing Date	December 15, 2003
				First Named Inventor	Kie Y. Ahn
				Art Unit	2826
				Examiner Name	L. Andujar
Sheet	1	of	1	Attorney Docket Number	M4065.0383/P383-B

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number+Kind Code ² (if known)			

FOREIGN PATENT DOCUMENTS						
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		Country Code ³ +Number ⁴ +Kind Code ⁵ (if known)				

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W	CA	S. Wolf, Ph.D., et al., "Silicon Processing for the VLSI Era," Chemical Vapor Deposition of Amorphous and Polycrystalline Films, Volume 1, Process Technology, pp. 182-183.	

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Examiner Signature		Date Considered	10/18/2005
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